


<b>Search Notes</b> 	<b>Application/Control No.</b>  10600087	<b>Applicant(s)/Patent Under Reexamination</b>  MARUYA, MAKOTO
	<b>Examiner</b>  Chawan, Sheela C	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	144,154,	1/7/07	SCC
370	538,465,385,	1/7/07	SCC
348	42,145,169,143,144	1/7/07	SCC
351	57,158	1/7/07	SCC
124	87	1/7/07	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
EAST, US-PGPUB,USPAT,EPO,JPO,DERWENT,IBM-TDB.	1/7/07	SCC
INVENTOR NAME SEARCH.	1/7/07	SCC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner